

# Electronic Devices

## Mid Term Lecture - 02

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Reference book:

**Electronic Devices and Circuit Theory (Chapter-1)**

Robert L. Boylestad and L. Nashelsky , (11<sup>th</sup> Edition)



# Objectives

- Develop a clear understanding of the basic operation and characteristics of a diode in the no-bias, forward-bias, and reverse-bias regions.
- Be able to calculate the dc, ac, and average ac resistance of a diode from the characteristics.
- Understand the impact of an equivalent circuit whether it is ideal or practical.
- Become familiar with the operation and characteristics of a Zener diode and light-emitting diode.

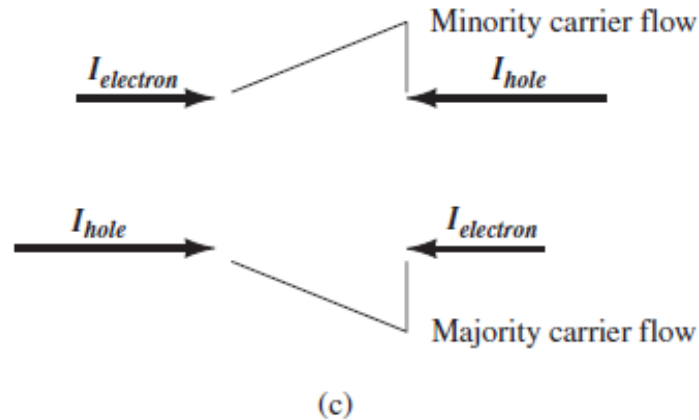
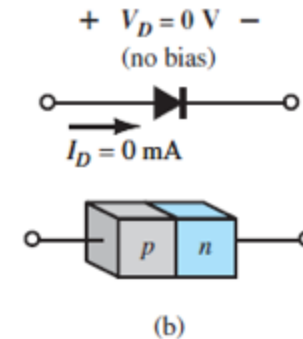
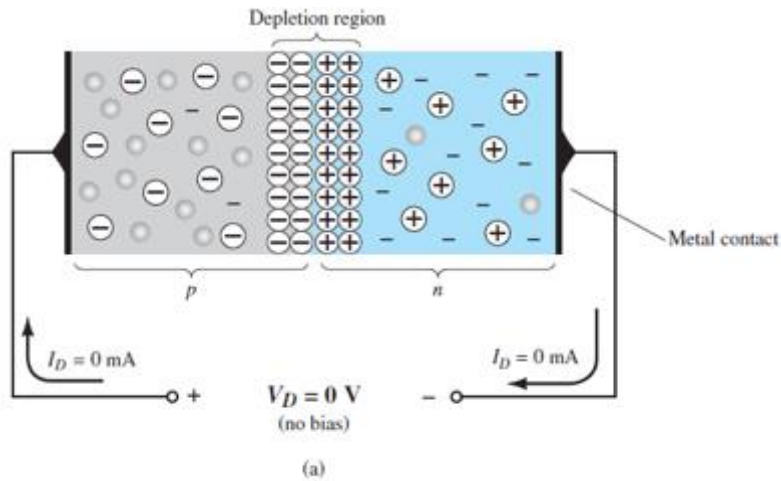


# Semiconductor Diode: No Applied Bias ( $V=0$ V)

- ❖ Now that both n – and p -type materials are available, we can construct our first solid-state electronic device: The semiconductor diode , with applications too numerous to mention, is created by simply joining an n -type and a p -type material together.
- ❖ *In the absence of an applied bias* across a semiconductor diode, *the net flow of charge in one direction is zero.*



# No Applied Bias ( $V_D = 0$ V)

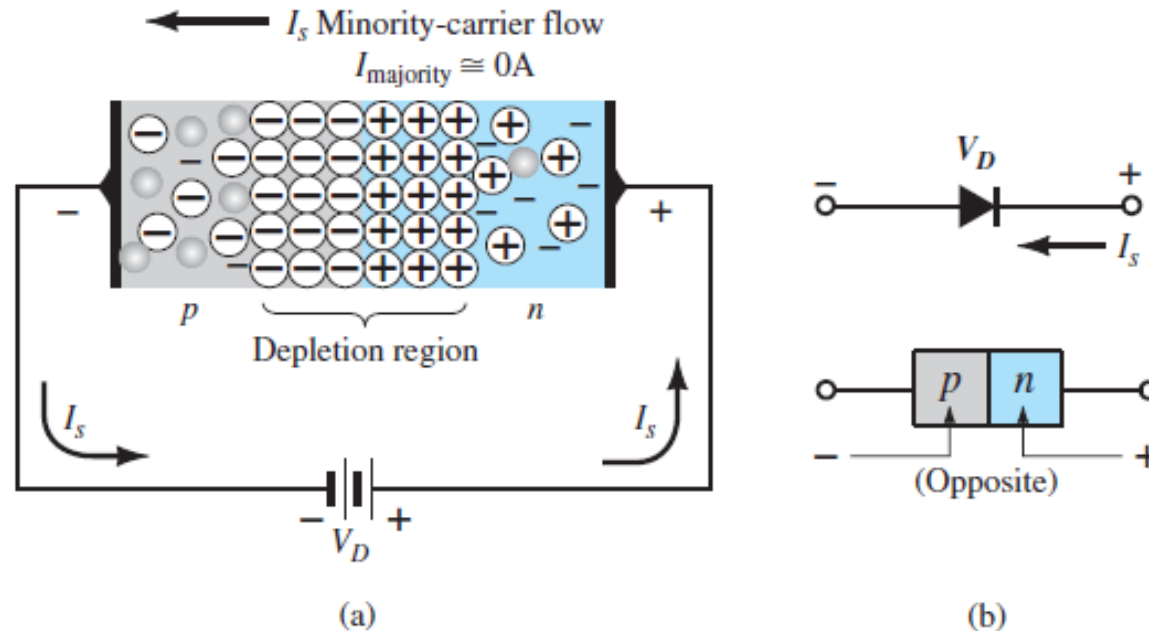


**FIG. 1.12**

A p-n junction with no external bias: (a) an internal distribution of charge; (b) a diode symbol, with the defined polarity and the current direction; (c) demonstration that the net carrier flow is zero at the external terminal of the device when  $V_D = 0$  V.

# Reverse-Bias Condition ( $V_D < 0$ V)

The current that exists under reverse-bias conditions is called the reverse saturation current and is represented by  $I_s$ .

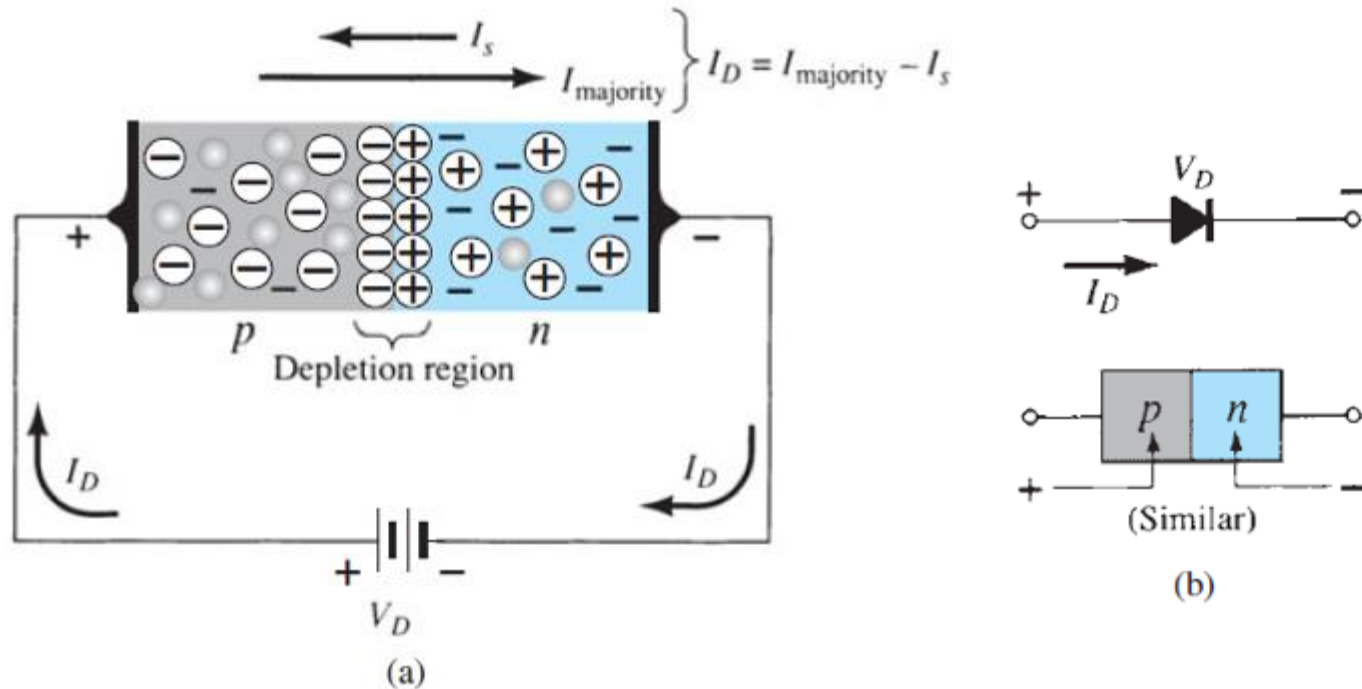


**FIG. 1.13**

*Reverse-biased p-n junction: (a) internal distribution of charge under reverse-bias conditions; (b) reverse-bias polarity and direction of reverse saturation current.*

### Forward-Bias Condition ( $V_D > 0$ V)

**A *forward-bias* or “on” condition is established by applying the positive potential to the  $p$  -type material and the negative potential to the  $n$  -type material as shown in Fig. 1.14 .**



**FIG. 1.14**

*Forward-biased p-n junction: (a) internal distribution of charge under forward-bias conditions; (b) forward-bias polarity and direction of resulting current.*

# Forward-Bias Condition ( $V_D > 0$ V) Contd.

- ❖ It can be demonstrated through the use of solid-state physics that the general characteristics of a semiconductor diode can be defined by the following equation, referred to as Shockley's equation, for the forward- and reverse-bias regions:

$$I_D = I_s(e^{V_D/nV_T} - 1) \quad (\text{A})$$

Where,  $I_s$  is the reverse saturation current

$V_D$  is the applied forward-bias voltage across the diode

$n$  is an ideality factor, which is a function of the operating conditions and physical construction; it has a range between 1 and 2 depending on a wide variety of factors ( $n = 1$  will be assumed throughout this text unless otherwise noted).



# Forward-Bias Condition ( $V_D > 0$ V) Contd.

- The voltage  $V_T$  in Eq. (1.1) is called the thermal voltage and is determined by:

$$V_T = \frac{kT_K}{q} \quad (\text{V})$$

where

$k$  is Boltzmann's constant =  $1.38 \times 10^{-23}$  J/K

$T_K$  is the absolute temperature in kelvins = 273 + the temperature in  $^{\circ}\text{C}$

$q$  is the magnitude of electronic charge =  $1.6 \times 10^{-19}$  C

**EXAMPLE 1.1** At a temperature of  $27^{\circ}\text{C}$  (common temperature for components in an enclosed operating system), determine the thermal voltage  $V_T$ .

**Solution:** Substituting into Eq. (1.3), we obtain

$$\begin{aligned} T &= 273 + ^{\circ}\text{C} = 273 + 27 = 300 \text{ K} \\ V_T &= \frac{kT_K}{q} = \frac{(1.38 \times 10^{-23} \text{ J/K})(300 \text{ K})}{1.6 \times 10^{-19} \text{ C}} \\ &= 25.875 \text{ mV} \cong 26 \text{ mV} \end{aligned}$$

The thermal voltage will become an important parameter in the analysis to follow in this chapter and a number of those to follow.





# Semiconductor Diode Characteristics

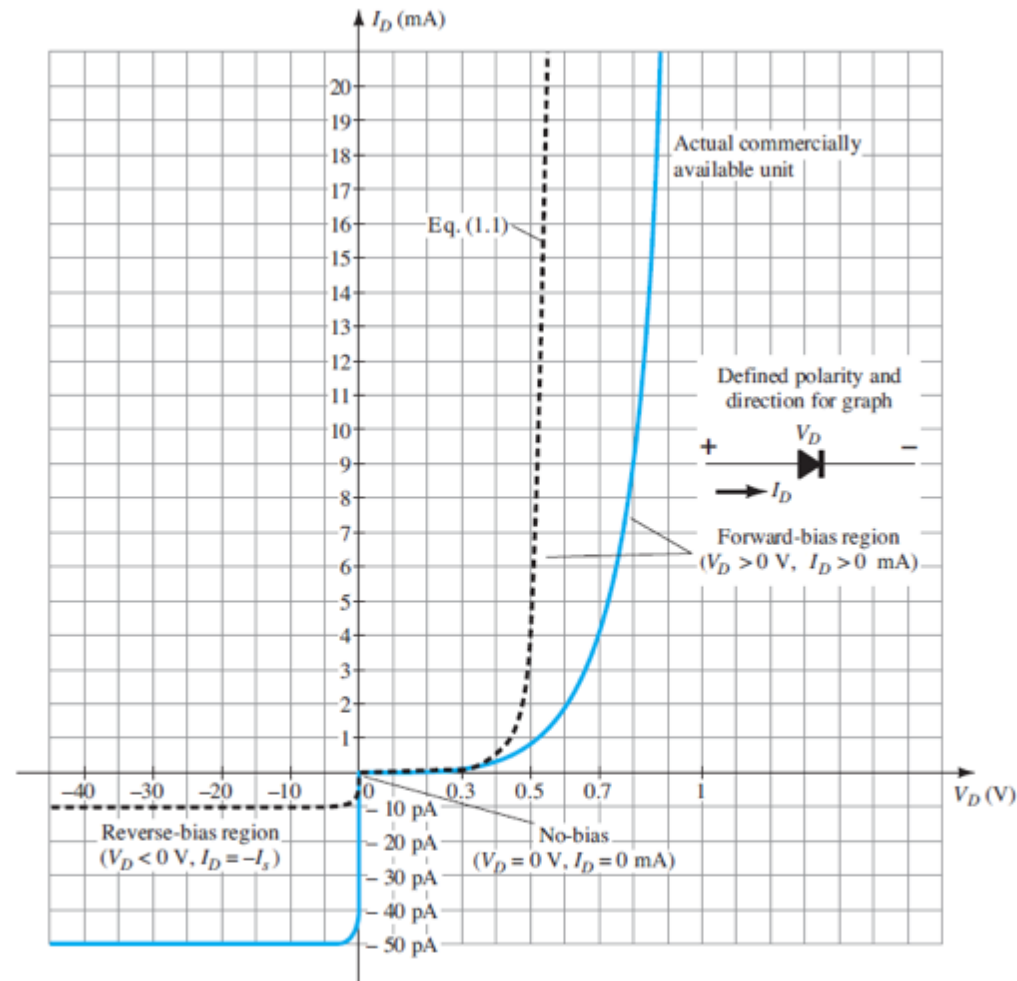
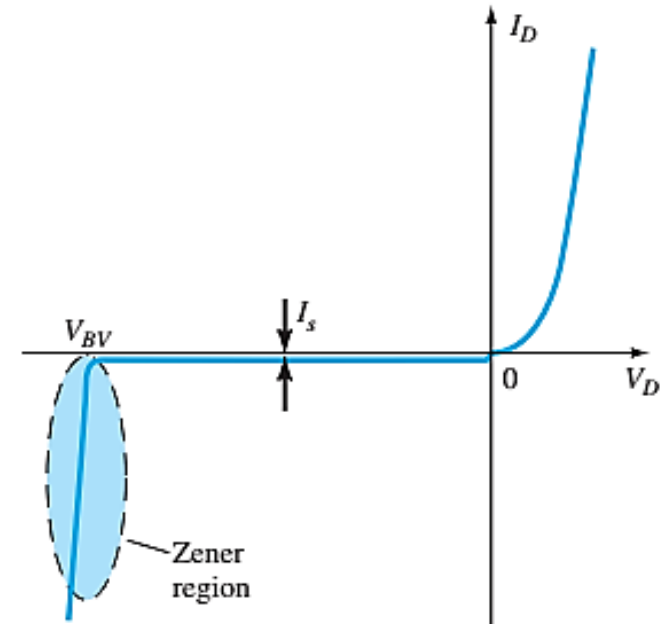


FIG. 1.15

Silicon semiconductor diode characteristics.

# Breakdown Region

- The maximum reverse-bias potential that can be applied before entering the breakdown region is called the peak inverse voltage (referred to simply as the PIV rating) or the peak reverse voltage (denoted the PRV rating).
- If an application requires a PIV rating greater than that of a single unit, a number of diodes of the same characteristics can be connected in series. Diodes are also connected in parallel to increase the current-carrying capacity.
- In general, the breakdown voltage of GaAs diodes is about 10% higher than those for silicon diodes but after 200% higher than levels for Ge diodes.



**FIG. 1.17**  
Breakdown region.



# Breakdown Region Contd.

- As the voltage across the diode increases in the reverse-bias region, the velocity of the minority carriers responsible for the reverse saturation current  $I_s$  will also increase.
- Eventually, their velocity and associated kinetic energy ( $W_K = \frac{1}{2}mv^2$ ) will be sufficient to release additional carriers through collisions with otherwise stable atomic structures.
- An ionization process will result whereby valence electrons absorb sufficient energy to leave the parent atom.
- These additional carriers can then aid the ionization process to the point where a high avalanche current is established and the avalanche breakdown region determined.

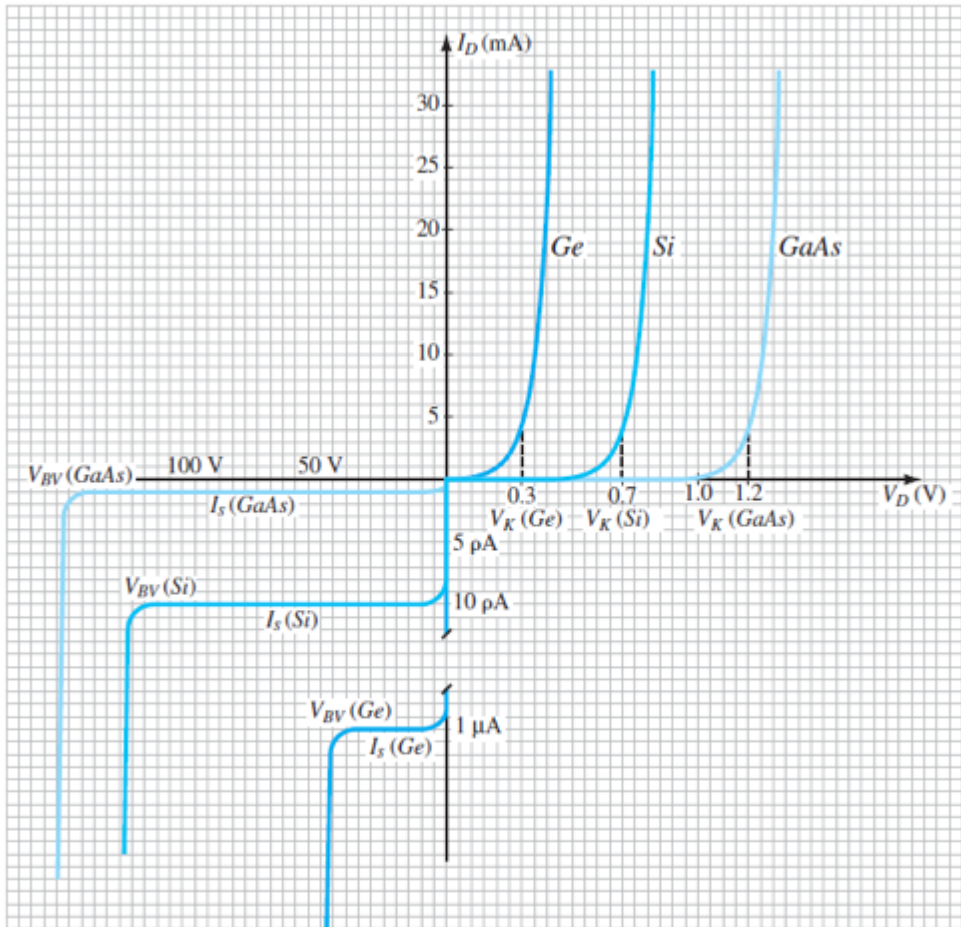


# Breakdown Region Contd.

- The avalanche region ( $V_{BV}$ ) can be brought closer to the vertical axis by increasing the doping levels in the p- and n-type materials.
- However, as  $V_{BV}$  decreases to very low levels, such as -5 V, another mechanism, called Zener breakdown, will contribute to the sharp change in the characteristic.
- It occurs because there is a strong electric field in the region of the junction that can disrupt the bonding forces within the atom and “generate” carriers.
- Although the Zener breakdown mechanism is a significant contributor only at lower levels of  $V_{BV}$ , this sharp change in the characteristic at any level is called the Zener region, and diodes employing this unique portion of the characteristic of a p–n junction are called Zener diodes.



# Ge, Si & GaAs



**FIG. 1.18**

*Comparison of Ge, Si, and GaAs commercial diodes.*

**TABLE 1.3**  
*Knee Voltages  $V_K$*

Semiconductor	$V_K$ (V)
Ge	0.3
Si	0.7
GaAs	1.2

# Temperature Effects

- In the forward-bias region the characteristics of a silicon diode shift to the left at a rate of 2.5 mV per centigrade degree increase in temperature.
- In the reverse-bias region the reverse current of a silicon diode doubles for every 10°C rise in temperature.
- The reverse breakdown voltage of a semiconductor diode will increase or decrease with temperature.
- As temperature increases it adds energy to the diode:
  - It reduces the required forward bias voltage for forward bias conduction.
  - It increases the amount of reverse current in the reverse bias condition.
  - It increases maximum reverse bias avalanche voltage.
- Germanium diodes are more sensitive to temperature variations than silicon or gallium arsenide diodes.



# Temperature Effect Contd.

*In the forward-bias region the characteristics of a silicon diode shift to the left at a rate of 2.5 mV per centigrade degree increase in temperature.*

*In the reverse-bias region the reverse current of a silicon diode doubles for every  $10^\circ\text{C}$  rise in temperature.*

*Finally, The reverse breakdown voltage of a semiconductor diode will increase or decrease with temperature.*

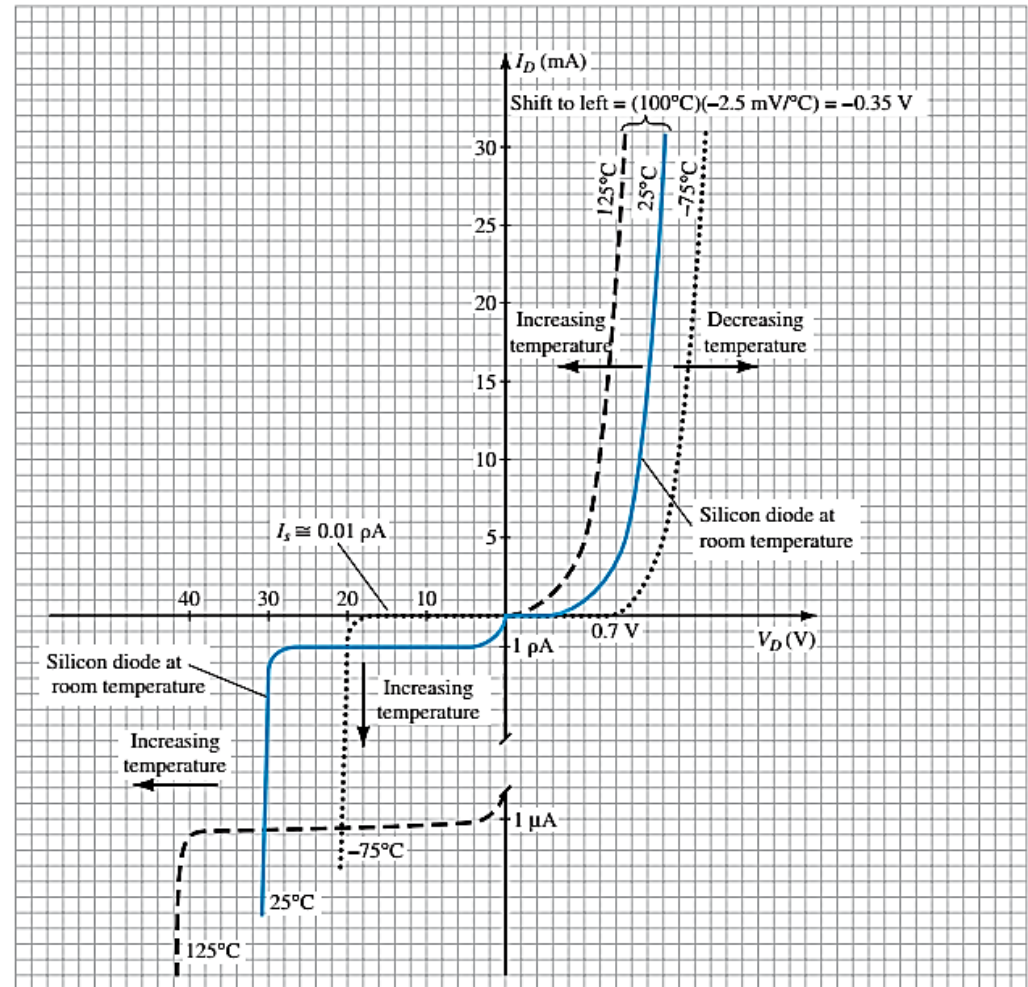


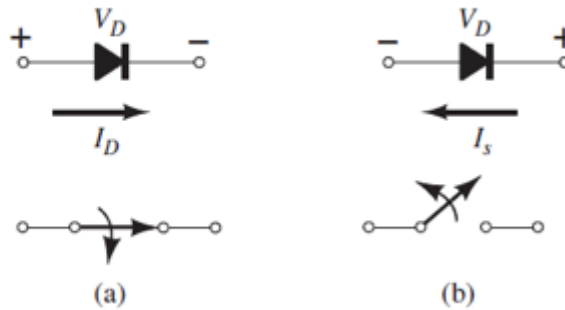
FIG. 1.19

Variation in Si diode characteristics with temperature change.



# Ideal vs Practical

- The semiconductor diode behaves in a manner similar to a mechanical switch in that it can control whether current will flow between its two terminals.
- The semiconductor diode is different from a mechanical switch in the sense that when the switch is closed it will only permit current to flow in one direction.



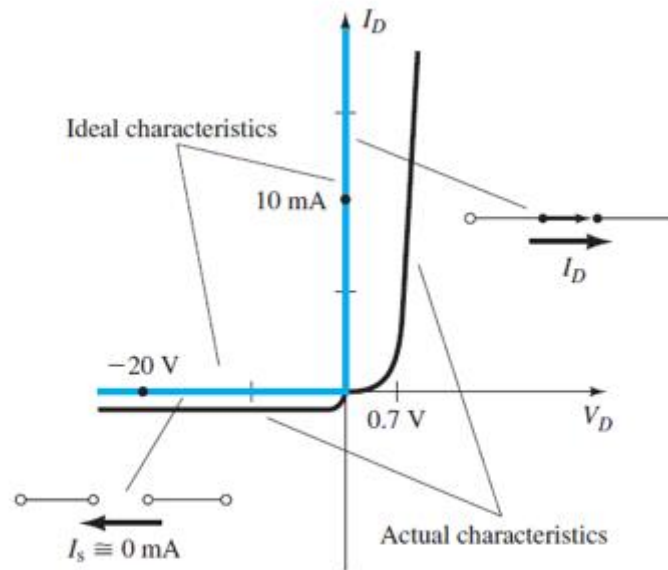
**FIG. 1.21**

*Ideal semiconductor diode: (a) forward-biased; (b) reverse-biased.*



# Ideal vs Practical Contd.

- Ideally, if the semiconductor diode is to behave like a closed switch in the forward-bias region, the resistance of the diode should be  $0\ \Omega$ .
- In the reverse-bias region its resistance should be  $\infty\ \Omega$  to represent the open-circuit equivalent.



**FIG. 1.22**

*Ideal versus actual semiconductor characteristics.*

# Resistance Levels

- **Semiconductors react differently to DC and AC currents.**
- **There are three types of resistance:**
  - » **DC (static) resistance**
  - » **AC (dynamic) resistance**
  - » **Average AC resistance**

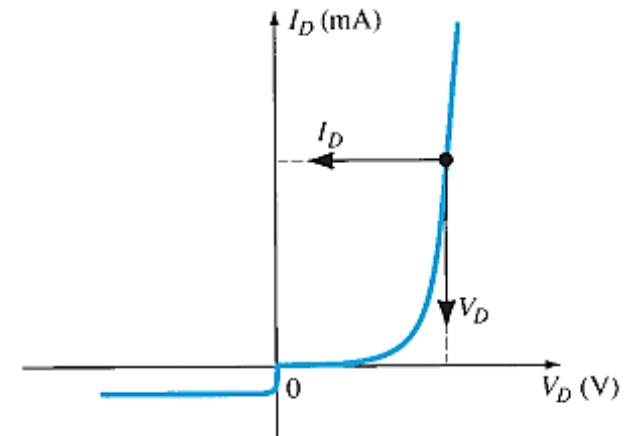


# DC or Static Resistance

- For a specific applied DC voltage  $V_D$ , the diode has a specific current  $I_D$ , and a specific resistance  $R_D$ .

$$R_D = \frac{V_D}{I_D}$$

- In general, therefore, the higher the current through a diode, the lower is the dc resistance level.

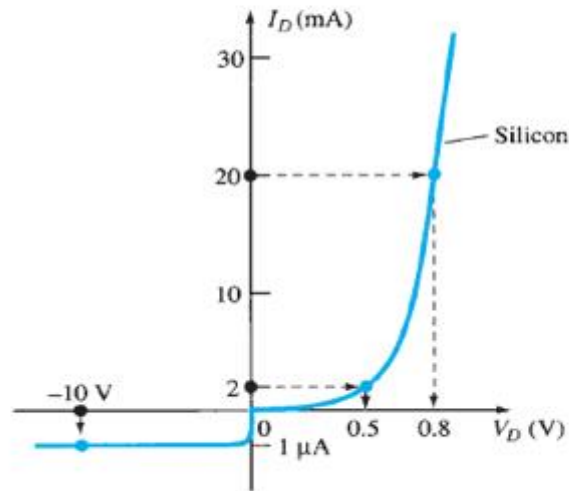


**FIG. 1.23**

*Determining the dc resistance of a diode at a particular operating point.*

**EXAMPLE 1.3** Determine the dc resistance levels for the diode of Fig. 1.24 at

- a.  $I_D = 2 \text{ mA}$  (low level)
- b.  $I_D = 20 \text{ mA}$  (high level)
- c.  $V_D = -10 \text{ V}$  (reverse-biased)



**FIG. 1.24**

Example 1.3.

**Solution:**

- a. At  $I_D = 2 \text{ mA}$ ,  $V_D = 0.5 \text{ V}$  (from the curve) and

$$R_D = \frac{V_D}{I_D} = \frac{0.5 \text{ V}}{2 \text{ mA}} = 250 \Omega$$

- b. At  $I_D = 20 \text{ mA}$ ,  $V_D = 0.8 \text{ V}$  (from the curve) and

$$R_D = \frac{V_D}{I_D} = \frac{0.8 \text{ V}}{20 \text{ mA}} = 40 \Omega$$

- c. At  $V_D = -10 \text{ V}$ ,  $I_D = -I_s = -1 \mu\text{A}$  (from the curve) and

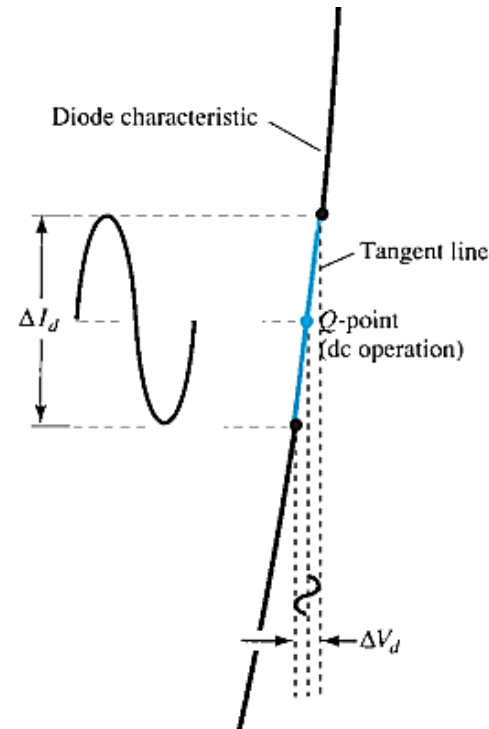
$$R_D = \frac{V_D}{I_D} = \frac{10 \text{ V}}{1 \mu\text{A}} = 10 \text{ M}\Omega$$

clearly supporting some of the earlier comments regarding the dc resistance levels of a diode.



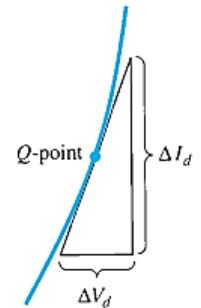
# AC or Dynamic Resistance

- The dc resistance of a diode is independent of the shape of the characteristic in the region surrounding the point of interest.
- The designation Q-point is derived from the word quiescent, which means “still or unvarying.”
- In general, therefore, the lower the Q-point of operation (smaller current or lower voltage), the higher is the ac resistance.
- **See Example 1.4.**



**FIG. 1.25**

*Defining the dynamic or ac resistance.*



**FIG. 1.26**

*Determining the ac resistance at a Q-point.*

# AC or Dynamic Resistance Contd.

- In the forward bias region:

$$r'_d = \frac{26 \text{ mV}}{I_D} + r_B \text{ ohms}$$

- The resistance depends on the amount of current ( $I_D$ ) in the diode.
- The voltage across the diode is fairly constant (26 mV for 25°C).
- $r_B$  ranges from a typical 0.1  $\Omega$  for high power devices to 2  $\Omega$  for low power, general purpose diodes. In some cases  $r_B$  can be ignored.
- In the reverse bias region:  $r'_d = \infty$

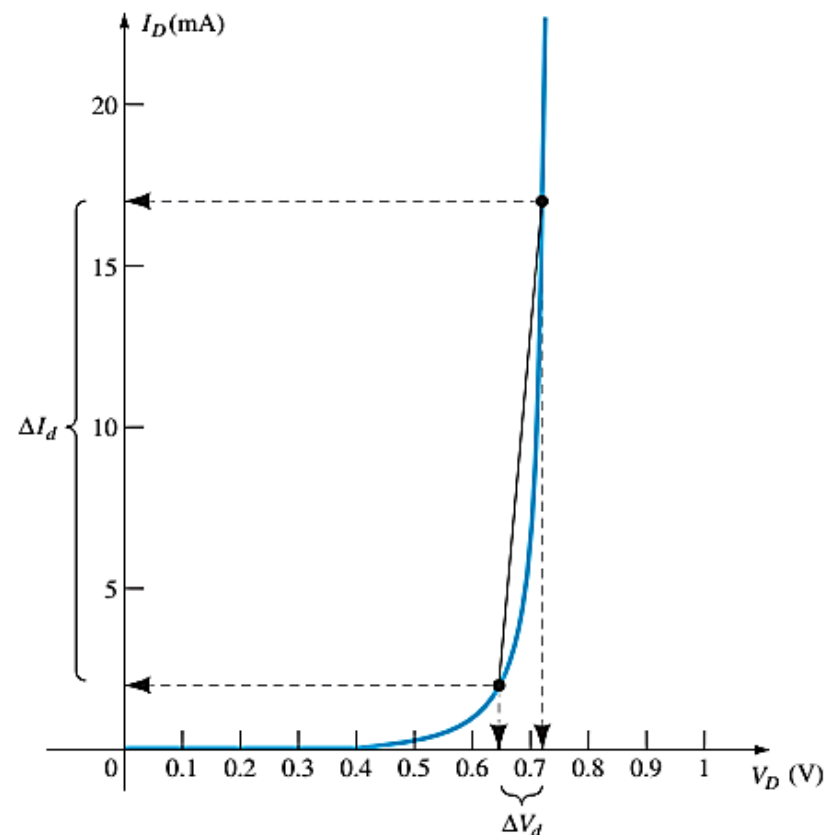
The resistance is effectively infinite. The diode acts like an open.



# Average AC or Resistance

- The average ac resistance is, by definition, the resistance determined by a straight line drawn between the two intersections established by the maximum and minimum values of input voltage.

$$r_{av} = \left. \frac{\Delta V_d}{\Delta I_d} \right|_{\text{pt. to pt.}}$$

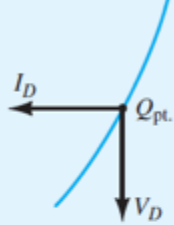
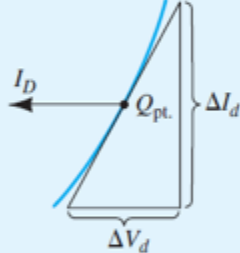
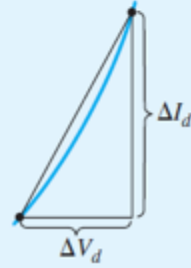


**FIG. 1.28**

*Determining the average ac resistance between indicated limits.*

# Summary table

**TABLE 1.6**  
*Resistance Levels*

Type	Equation	Special Characteristics	Graphical Determination
DC or static	$R_D = \frac{V_D}{I_D}$	Defined as a point on the characteristics	
AC or dynamic	$r_d = \frac{\Delta V_d}{\Delta I_d} = \frac{26 \text{ mV}}{I_D}$	Defined by a tangent line at the $Q$ -point	
Average ac	$r_{av} = \left. \frac{\Delta V_d}{\Delta I_d} \right _{\text{pt. to pt.}}$	Defined by a straight line between limits of operation	

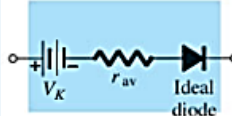
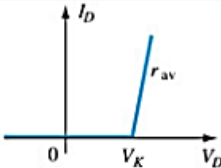

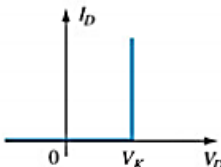
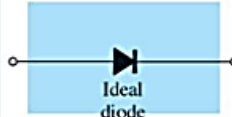
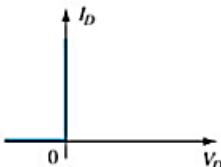


# Diode Equivalent Circuits

An equivalent circuit is a combination of elements properly chosen to best represent the actual terminal characteristics of a device or system in a particular operating region.

**TABLE 1.7**

*Diode Equivalent Circuits (Models)*

Type	Conditions	Model	Characteristics
Piecewise-linear model			
Simplified model	$R_{\text{network}} \gg r_{\text{av}}$		
Ideal device	$R_{\text{network}} \gg r_{\text{av}}$ $E_{\text{network}} \gg V_K$		



# Thank You

